

## ESD TEST REPORT

Human Body Model
JS-001-2017

ANSI/ESDA/JEDEC Standard, Method JS-001-2017 is an ESD test using Human Body Model where "R = 1500 ohm", "C = 100pf", one positive and one negative pulses applied to the devices per customer's specification with a minimum of 0.1 second cool down between pulses.

**Customer :** **Alpha & Omega Semiconductor (Shanghai), Ltd.**

**Address:** Building 8 & 9, No. 91, Lane 109, Rong Kang Road,  
Songjiang Export Processing Zone, Zone B, # 888 Song Zheng Highroad, Shanghai

### Device Information

Part No. :	AO4264C	Sample Size :	11pcs
Package Type :	SO8	Pin Count :	8
Lot No. :	NL005	Date Code :	-
VDD Domains :	D	VSS Domains :	S

### Test Equipment

Tester :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jan 14 <sup>th</sup> 2021	Expiration Date :	Jan 13 <sup>th</sup> 2022

### Environmental Condition

Temperature :	23°C	Humidity :	50% RH
Submit date :	Apr 21 <sup>st</sup> 2021	Complete date :	Apr 21 <sup>st</sup> 2021

### Curve Trace Criteria

	Pin Combinations	Force Voltage	Limit current
D	Vs. S & G	-30V ~ +30V	50µA

Curve Trace Results Within 10% range.

Stress Summary
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G TO S			
Sample No.	Stress Type	Voltage Level	Spot Test Results* (Within 10μA @ 20V between G and D/S)
1#	HBM	+3.4kV	FAILED
2#	HBM	±3.3kV	PASS
3#	HBM	±3.3kV	PASS
4#	HBM	±3.3kV	PASS


G TO D			
Sample No.	Stress Type	Voltage Level	Spot Test Results* (Within 10μA @ 20V between G and D/S)
5#	HBM	-3.4kV	FAILED
6#	HBM	±3.3kV	PASS
7#	HBM	±3.3kV	PASS
8#	HBM	±3.3kV	PASS

D TO S			
Sample No.	Stress Type	Voltage Level	Spot Test Results* (Within 10μA @ 20V between G and D/S)
9#	HBM	±8kV	PASS
10#	HBM	±8kV	PASS
11#	HBM	±8kV	PASS

### Test Result\*

Model	Pin Combinations	ESD Sensitivity Pass*: <b>3.3kV</b>	V Class
HBM	G vs. S	$\pm 3.3\text{kV}$	2 JS-001-2017 Class 0Z: <50V Class 0A: 50V~124V Class 0B: 125V~249V Class 1A: 250V~499V Class 1B: 500V~999V Class 1C: 1000V~1999V Class 2: 2000V~3999V Class 3A: 4000V~7999V Class 3B: $\geq 8000\text{V}$
	G vs. D	$\pm 3.3\text{kV}$	
	D vs. S	$\pm 8\text{kV}$	

\*Note: Results will be updated based on customer final electrical test results.

Test Engineer: Wenping Yan	Date: Apr 21 <sup>st</sup> 2021
Approved by FA Manager: 	Date: Apr 21 <sup>st</sup> 2021



### Recommendations

**EAG Shanghai** certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

**EAG Shanghai** recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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